

## 100V N-Channel Enhancement Mode MOSFET

### Description

The AP120N10D uses advanced **APM-SGT<sub>11</sub>** technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 100V$   $I_D = 120A$

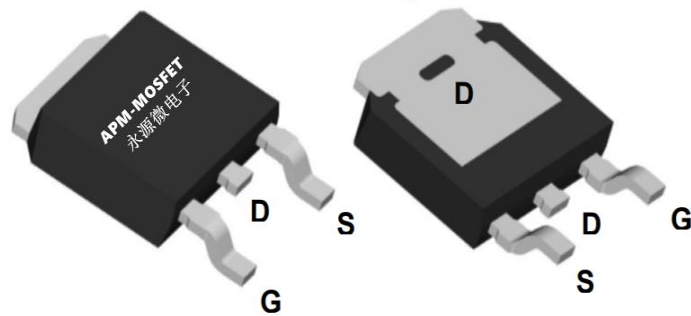
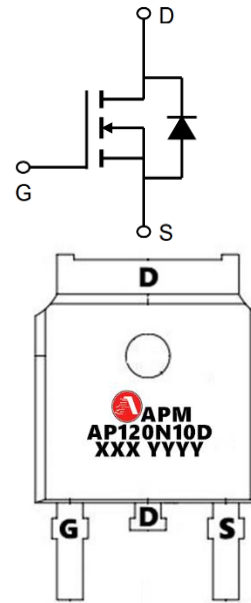
$R_{DS(ON)} < 7.5m\Omega$  @  $V_{GS}=10V$  (Type: **6.2mΩ**)

### Application

DC/DC Converter

LED Backlighting

Power Management Switches



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP120N10D	TO-252-3L	AP120N10D XXX YYYY	2500

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	100	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D@T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V	120	A
$I_D@T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V	63.5	A
IDM	Pulsed Drain Current	340	A
EAS	Single Pulse Avalanche Energy	135.2	mJ
IAS	Avalanche Current	26	A
$P_D@T_C=25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	104	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient	1.2	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case	62	$^\circ\text{C}/\text{W}$



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### Electrical Characteristics (T<sub>c</sub>=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	100	-	-	V
IGSS	Gate-Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V	-	-	±100	nA
IDSS	Zero Gate Voltage Drain Current T <sub>J</sub> =25°C	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V	-	-	1	μA
	Zero Gate Voltage Drain Current T <sub>J</sub> =100°C		-	-	100	
VGS(th)	Gate-Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2.5	3.0	3.5	V
RDS(on)	Drain-Source on-Resistance <sup>4</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	6.2	7.5	mΩ
gfs	Forward Transconductance <sup>4</sup>	V <sub>DS</sub> =10V, I <sub>D</sub> =20A	-	52	-	S
Ciss	Input Capacitance	V <sub>DS</sub> = 50V, V <sub>GS</sub> =0V, f=1MHz	-	1480	-	pF
Coss	Output Capacitance		-	736	-	
Crss	Reverse Transfer Capacitance		-	18	-	
R <sub>G</sub>	Gate Resistance	f=1MHz	-	2.5	-	Ω
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =50V, I <sub>D</sub> =20A	-	23	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	6.6	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	5.7	-	
td(on)	Turn-on Delay Time	V <sub>GS</sub> =10V, V <sub>DD</sub> =50V, R <sub>G</sub> =3Ω, I <sub>D</sub> =20A	-	9.3	-	ns
t <sub>r</sub>	Rise Time		-	8.4	-	
td(off)	Turn-off Delay Time		-	18	-	
t <sub>f</sub>	Fall Time		-	8.9	-	
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, di/dt=100A/μs	-	52	-	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	87	-	nC
IS	Continuous Source Current T <sub>c</sub> =25°C	I <sub>S</sub> =20A, V <sub>GS</sub> =0V	-	-	120	A
VSD	Diode Forward Voltage <sup>4</sup>		-	-	1.2	V

#### Notes:

- 1、 The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、 The EAS data shows Max. rating . The test condition is V<sub>DD</sub>=50V, V<sub>GS</sub>=10V, L=0.4mH, I<sub>AS</sub>=42A
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation.

Typical Characteristics

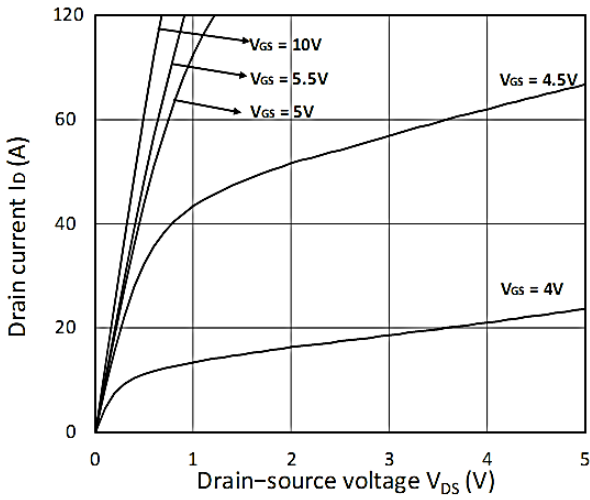


Figure 1. Output Characteristics

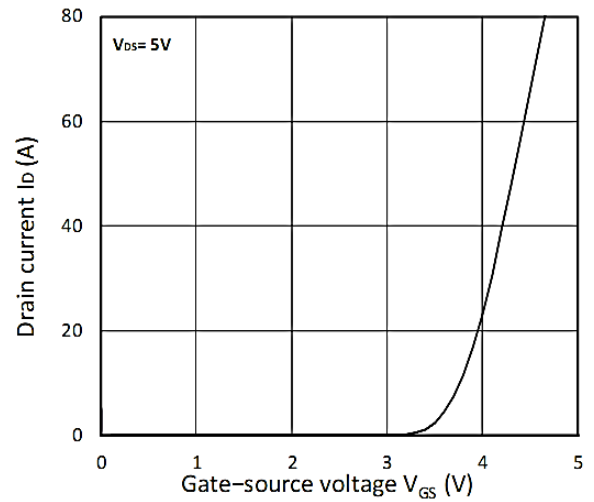


Figure 2. Transfer Characteristics

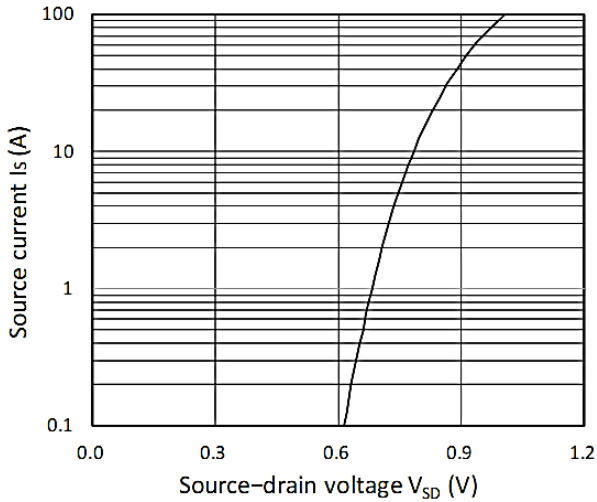


Figure 3. Forward Characteristics of Reverse

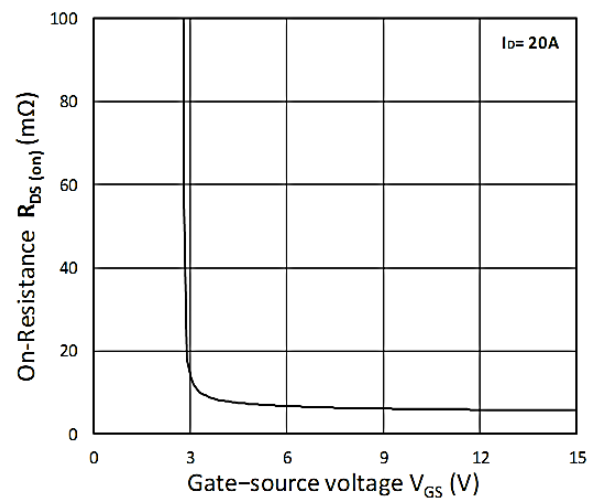


Figure 4.  $R_{DS(ON)}$  vs.  $V_{GS}$

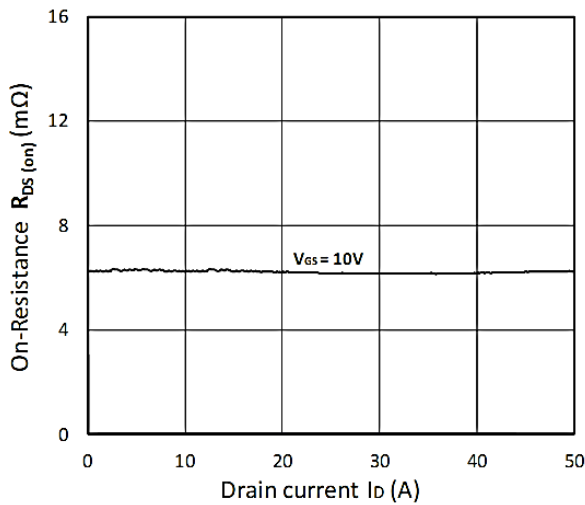


Figure 5.  $R_{DS(ON)}$  vs.  $I_D$

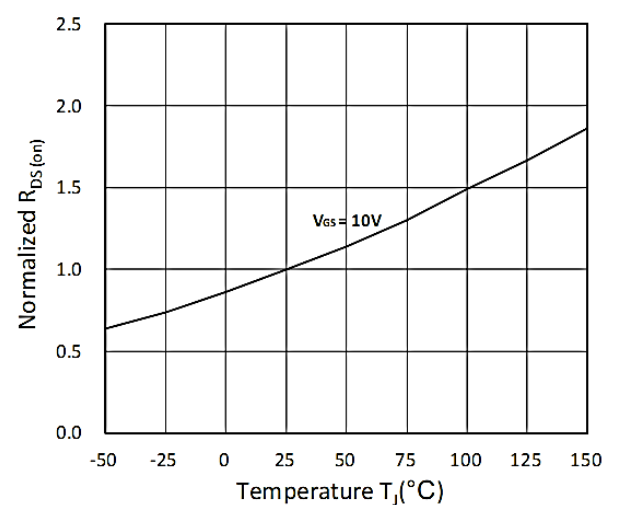
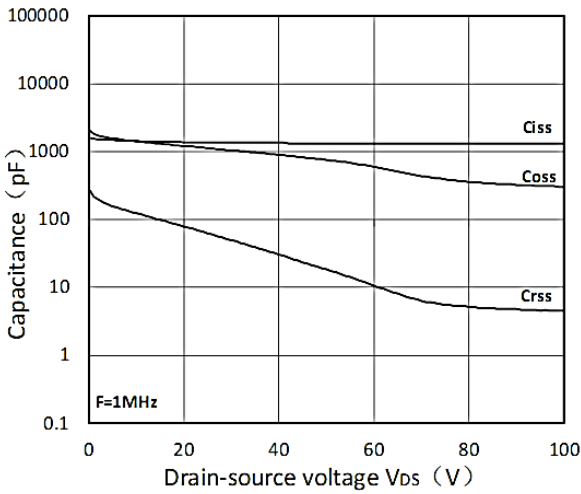
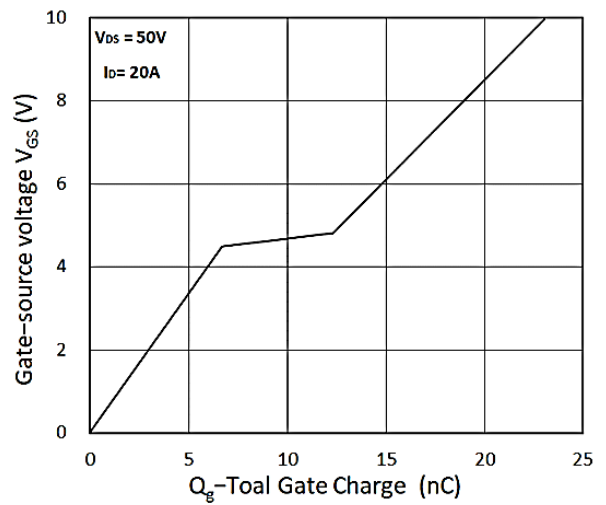


Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature

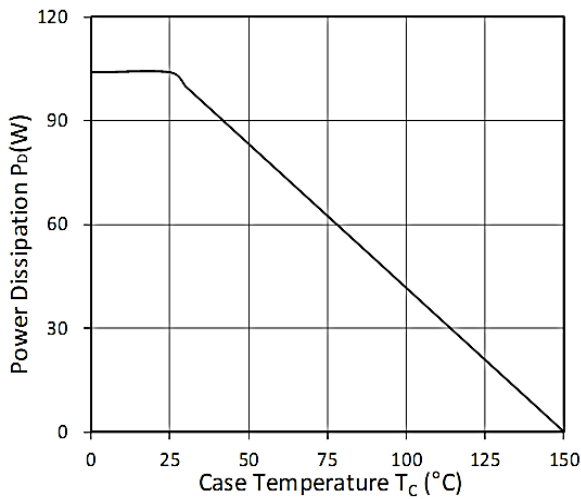
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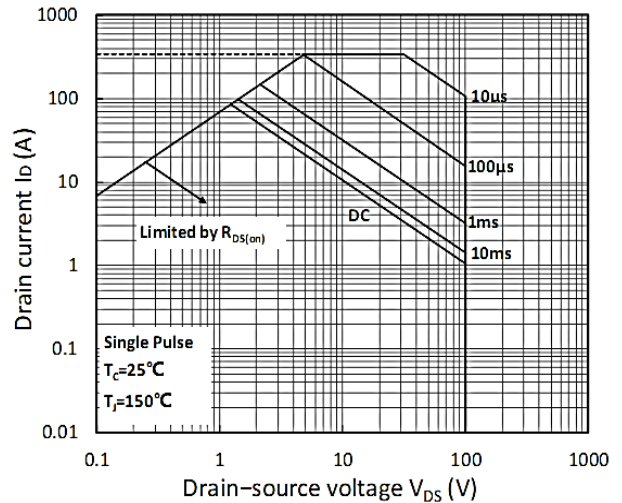
**Figure 7. Capacitance Characteristics**



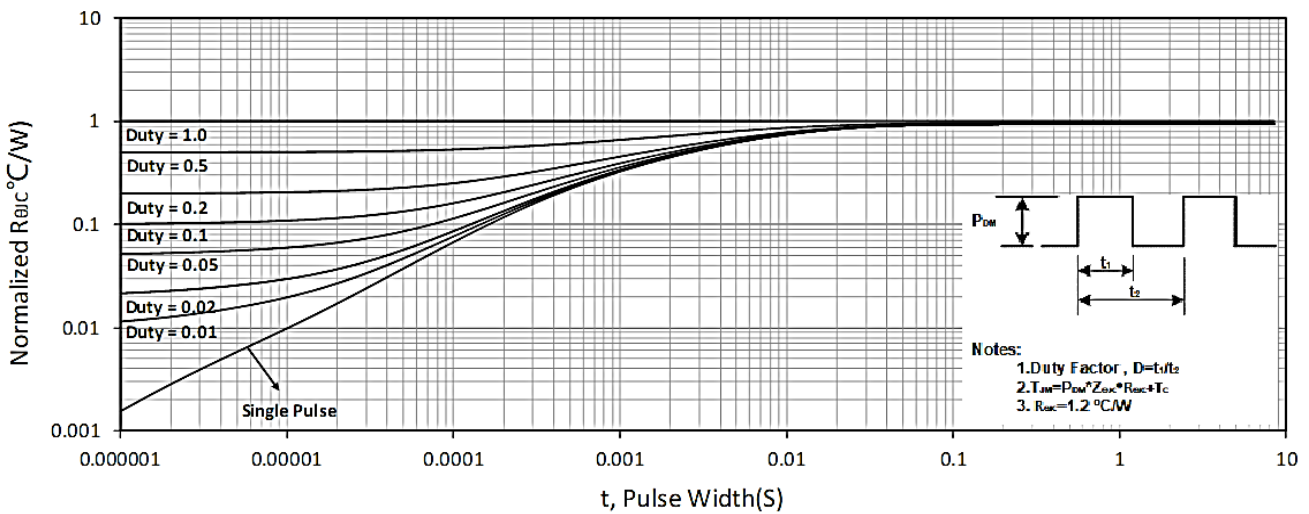
**Figure 8. Gate Charge Characteristics**



**Figure 9. Power Dissipation**

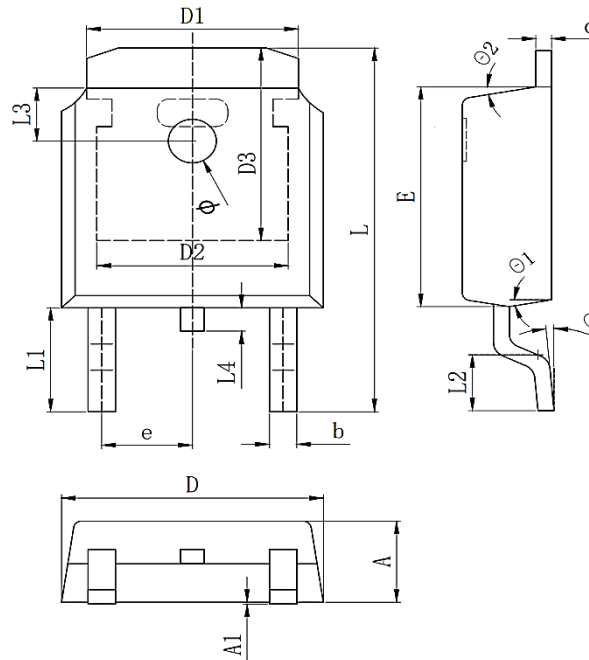


**Figure 10. Safe Operating Area**



**Figure 11. Normalized Maximum Transient Thermal Impedance**

### Package Mechanical Data-TO-252-3L



Symbol	Dim in mm		
	Min	Typ	Max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
$\phi$	1.1	1.2	1.3
$\theta$	0°		10°
$\theta_1$	5°		10°
$\theta_2$	5°		10°

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Edition	Date	Change
REV1.0	2022/8/5	Initial release

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